

**Electrical Characteristics** $T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
<b>Off Characteristics</b>							
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$ $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	Q1 Q2	-20 20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$ $I_D = 250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	Q1 Q2		-14 12		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{ V}, V_{GS} = 0\text{ V}$ $V_{DS} = 16\text{ V}, V_{GS} = 0\text{ V}$	Q1 Q2			-1 1	$\mu\text{A}$
$I_{GSS}$	Gate-Body Leakage	$V_{GS} = \pm 12\text{ V}, V_{DS} = 0\text{ V}$ $V_{GS} = \pm 12\text{ V}, V_{DS} = 0\text{ V}$	Q1 Q2			$\pm 100$ $\pm 100$	nA

**On Characteristics (Note 2)**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$ $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	Q1 Q2	-0.6 0.6	-1.0 1.0	-1.5 1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$ $I_D = 250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	Q1 Q2		3 -3		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = -4.5\text{ V}, I_D = -4.2\text{ A}$ $V_{GS} = -2.5\text{ V}, I_D = -3.4\text{ A}$ $V_{GS} = -4.5\text{ V}, I_D = -4.2\text{ A}, T_J = 125^\circ\text{C}$ $V_{GS} = 4.5\text{ V}, I_D = 5.9\text{ A}$ $V_{GS} = 2.5\text{ V}, I_D = 4.9\text{ A}$ $V_{GS} = 4.5\text{ V}, I_D = 5.9\text{ A}, T_J = 125^\circ\text{C}$	Q1   Q2		45 65 58 23 33 31	55 82 73 27 39 39	m $\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = -5\text{ V}, I_D = -4.2\text{ A}$ $V_{DS} = 5\text{ V}, I_D = 5.9\text{ A}$	Q1 Q2		13 23		S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	Q1: $V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	Q1 Q2		753 677		pF
$C_{oss}$	Output Capacitance	Q2: $V_{DS} = 10\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	Q1 Q2		163 171		pF
$C_{rss}$	Reverse Transfer Capacitance		Q1 Q2		83 91		pF
$R_G$	Gate Resistance	$V_{GS} = 15\text{ mV}, f = 1.0\text{ MHz}$	Q1 Q2		8 2.2		$\Omega$

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	Q1: $V_{DD} = -10\text{ V}, I_D = -1\text{ A},$ $V_{GS} = -4.5\text{ V}, R_{GEN} = 6\text{ }\Omega$	Q1 Q2		13 11	23 20	ns
$t_r$	Turn-On Rise Time	Q2: $V_{DD} = 10\text{ V}, I_D = 1\text{ A},$ $V_{GS} = 4.5\text{ V}, R_{GEN} = 6\text{ }\Omega$	Q1 Q2		8 16	16 29	ns
$t_{d(off)}$	Turn-Off Delay Time		Q1 Q2		26 18	42 32	ns
$t_f$	Turn-Off Fall Time		Q1 Q2		14 7	52 14	ns
$Q_g$	Total Gate Charge	Q1: $V_{DS} = -10\text{ V}, I_D = -4.2\text{ A}, V_{GS} = -4.5\text{ V}$	Q1 Q2		7 6	10 8	nC
$Q_{gs}$	Gate-Source Charge	Q2: $V_{DS} = 10\text{ V}, I_D = 5.9\text{ A}, V_{GS} = 4.5\text{ V}$	Q1 Q2		1.6 1.5		nC
$Q_{gd}$	Gate-Drain Charge		Q1 Q2		1.9 1.8		nC

**Electrical Characteristics** (continued) $T_A = 25^\circ\text{C}$  unless otherwise noted

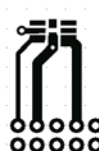
Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>							
$I_S$	Maximum Continuous Drain-Source Diode Forward Current		Q1 Q2			-1.3 1.3	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = -1.3\text{ A (Note 2)}$ $V_{GS} = 0\text{ V}, I_S = 1.3\text{ A (Note 2)}$	Q1 Q2		-0.8 0.7	-1.2 1.2	V
$t_{rr}$	Diode Reverse Recovery Time	$I_F = -4.2\text{ A}, dI_F/dt = 100\text{ A}/\mu\text{s}$ $I_F = 5.9\text{ A}, dI_F/dt = 100\text{ A}/\mu\text{s}$	Q1 Q2		17 15		nS
$Q_{rr}$	Diode Reverse Recovery Charge	$I_F = -4.2\text{ A}, dI_F/dt = 100\text{ A}/\mu\text{s}$ $I_F = 5.9\text{ A}, dI_F/dt = 100\text{ A}/\mu\text{s}$	Q1 Q2		6 4		nC

**Notes:**

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



- a)  $68^\circ\text{C}/\text{W}$  when mounted on a  $1\text{ in}^2$  pad of 2 oz copper (Single Operation).



- b)  $102^\circ\text{C}/\text{W}$  when mounted on a minimum pad of 2 oz copper (Single Operation).

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $< 300\mu\text{s}$ , Duty Cycle  $< 2.0\%$

## Typical Characteristics : Q1

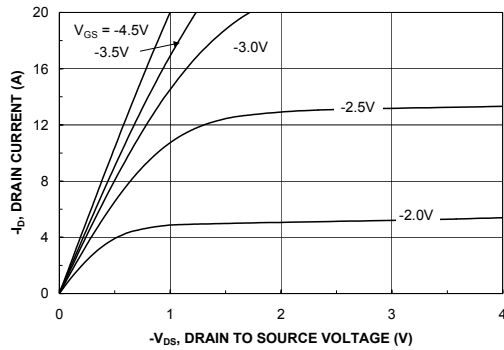


Figure 1. On-Region Characteristics.

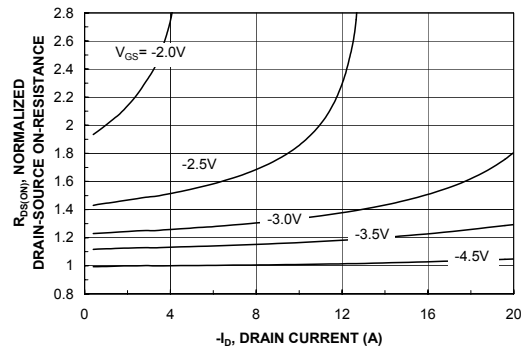


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

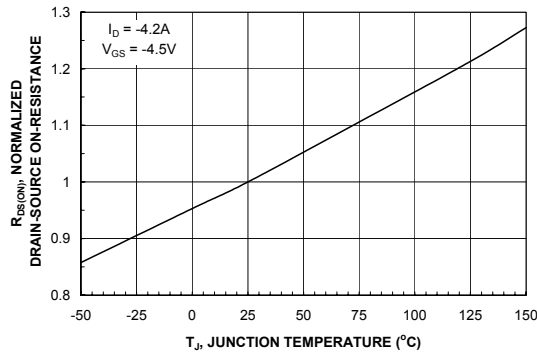


Figure 3. On-Resistance Variation with Temperature.

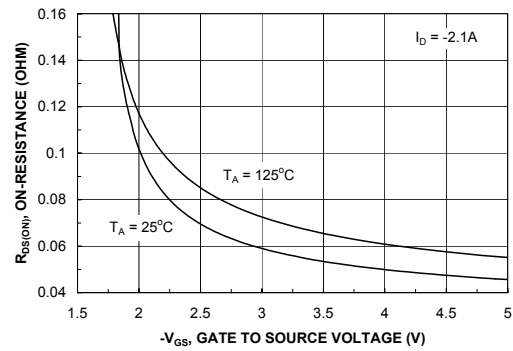


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

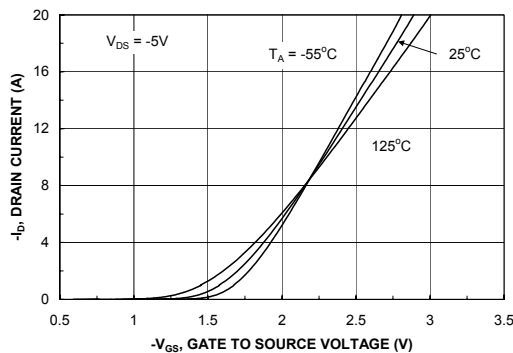


Figure 5. Transfer Characteristics.

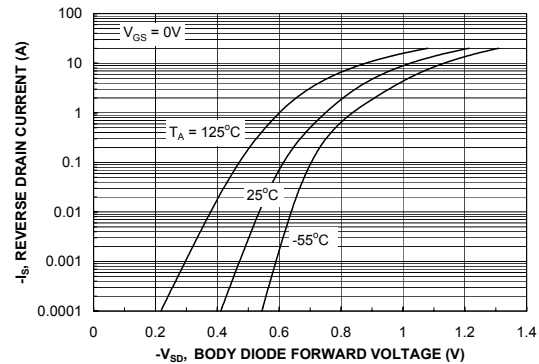


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Characteristics : Q1

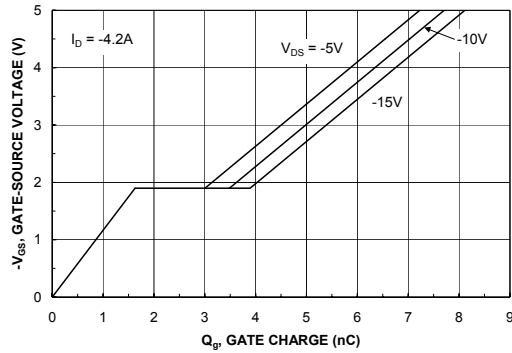


Figure 7. Gate Charge Characteristics.

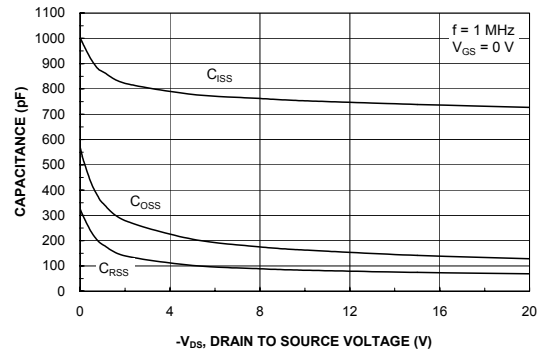


Figure 8. Capacitance Characteristics.

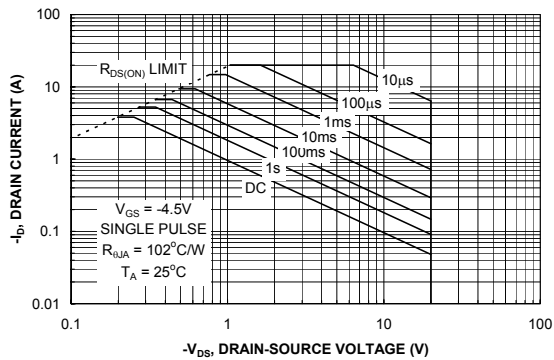


Figure 9. Maximum Safe Operating Area.

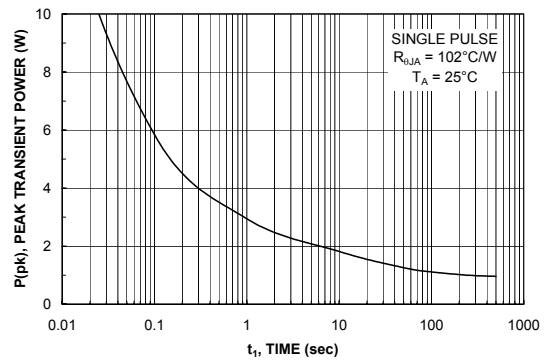


Figure 10. Single Pulse Maximum Power Dissipation.

## Typical Characteristics : Q2

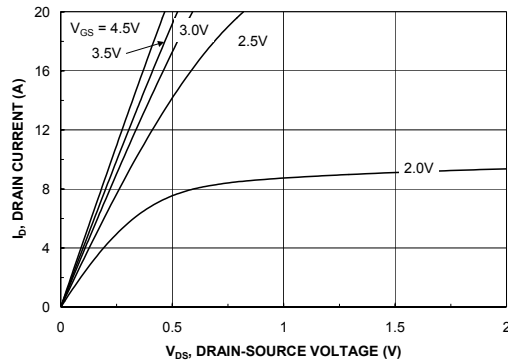


Figure 11. On-Region Characteristics.

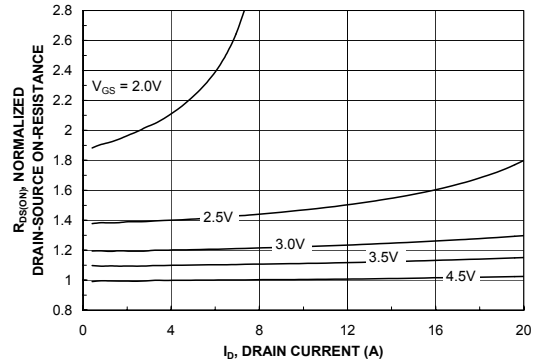


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

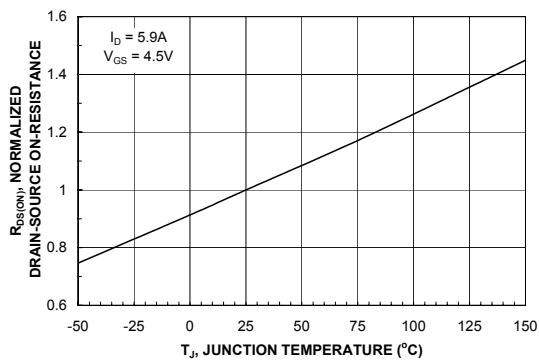


Figure 13. On-Resistance Variation with Temperature.

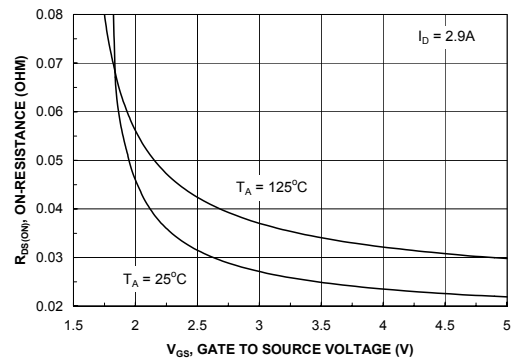


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

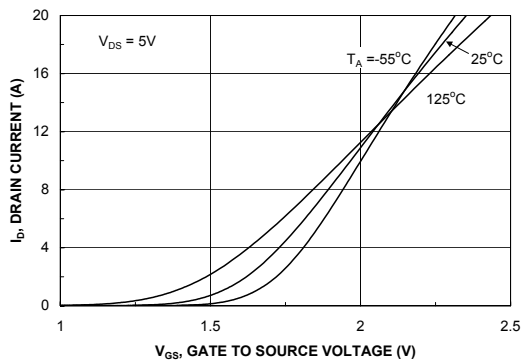


Figure 15. Transfer Characteristics.

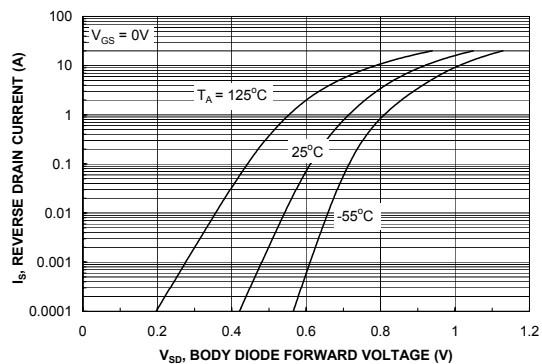


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Characteristics : Q2

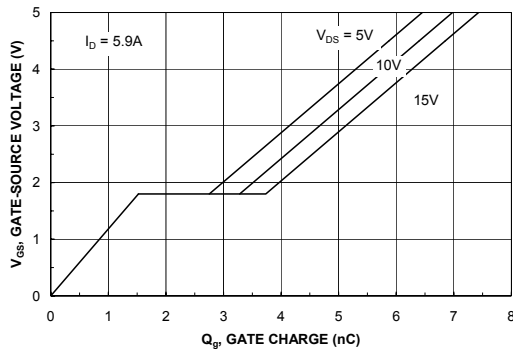


Figure 17. Gate Charge Characteristics.

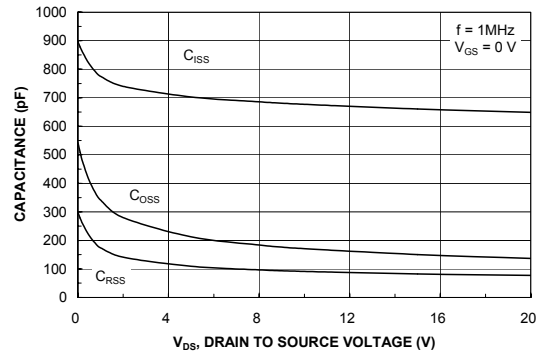


Figure 18. Capacitance Characteristics.

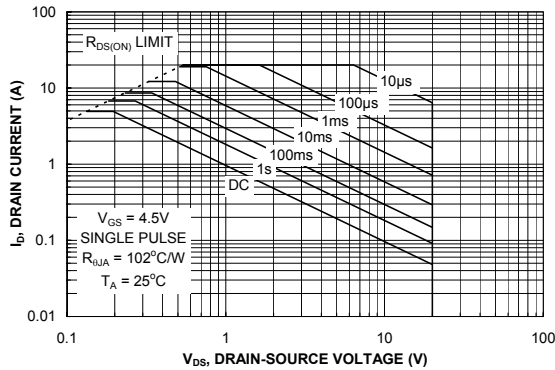


Figure 19. Maximum Safe Operating Area.

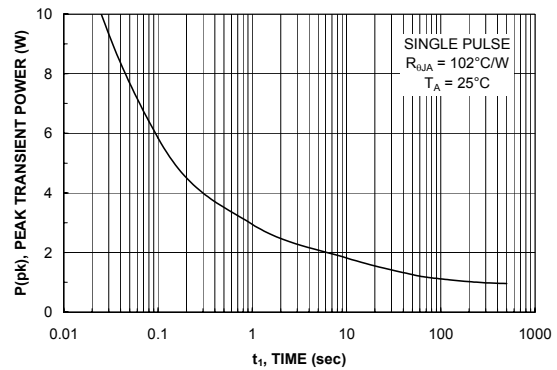


Figure 20. Single Pulse Maximum Power Dissipation.

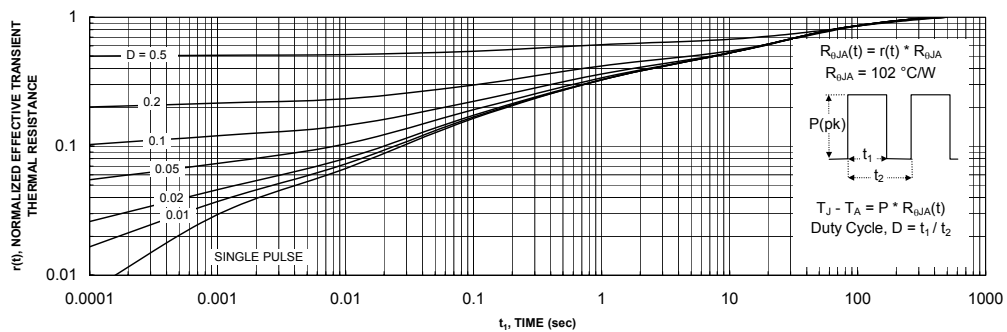
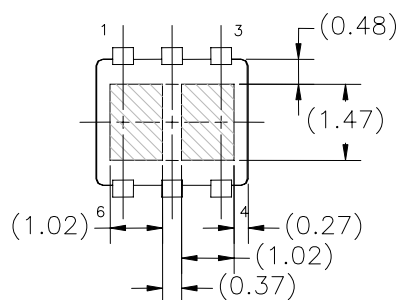


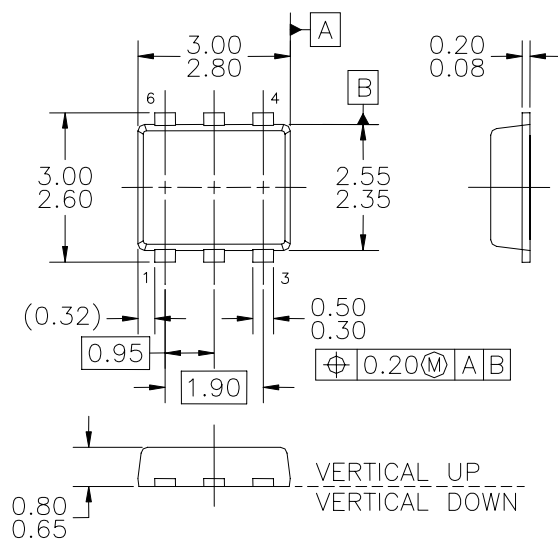
Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b.  
Transient thermal response will change depending on the circuit board design.

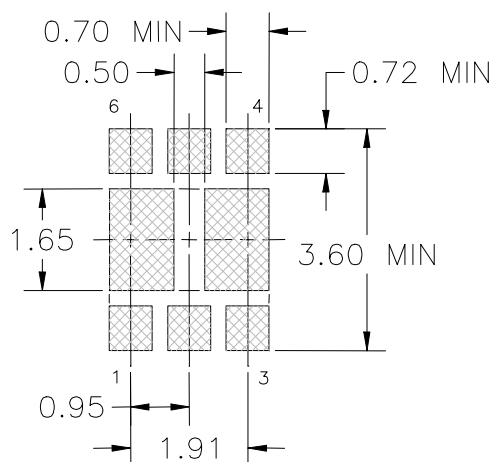
## Dimensional Outline and Pad Layout



### Bottom View



### Top View



## Recommended Landing Pattern For Standard Dual Configuration

NOTES: UNLESS OTHERWISE SPECIFIED

ALL DIMENSIONS ARE IN MILLIMETERS.

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